

# 30V N-Channel Trench MOSFET(Preliminary)

#### **Features**

- Trench Power Technology
- Low R<sub>DS(ON)</sub>
- Low Gate Charge
- Optimized for Fast-switching Applications

### **Applications**

- Synchronous Rectification in DC/DC and AC/DC Converters
- Isolated DC/DC Converters in Telecom and Industrial

#### **Product Summary**

VDS 30V

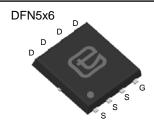
 $R_{DS(ON)}$  (at  $V_{GS}$ =10V) < 5m $\Omega$ 

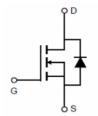
 $R_{DS(ON)}$  (at  $V_{GS}$ =4.5V) < 7m $\Omega$ 

 $I_D$  (at  $V_{GS}$ =10V) 90A

100% UIS Tested







Device	Package	Marking		
TTG90N03AT	DFN5x6	90N03AT		

<b>Absolute Maximum Ratings</b> $T_C = 25^{\circ}C$ , unless otherwise noted						
Parameter		Symbol	Value	Unit		
Drain-Source Voltage (V <sub>GS</sub> = 0V)		V <sub>DSS</sub>	30	V		
Continuous Drain Current B	T <sub>C</sub> = 25°C		51			
	$T_{\rm C} = 100^{\rm o}{\rm C}$	I <sub>D</sub>	51	A		
Pulsed Drain Current A		I <sub>DM</sub>	270	А		
Gate-Source Voltage		V <sub>GSS</sub>	±20	V		
Single Pulse Avalanche Energy L	=0.3mH <sup>A</sup>	E <sub>AS</sub>	72	mJ		
Avalanche Current A		I <sub>As</sub>	22	А		
	$T_{\rm C} = 25^{\rm o}{\rm C}$	P <sub>D</sub>	108	W		
Power Dissipation <sup>C</sup>	$T_{\rm C} = 100^{\rm o}{\rm C}$	P <sub>D</sub>	82	W		
Operating Junction and Storage Ten	perature Range	T <sub>J</sub> , T <sub>SGT</sub>	-55~+175	°C		

Thermal Resistance			
Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	rmal Resistance, Junction-to-Case R <sub>thJC</sub> 1.45		0000
Thermal Resistance, Junction-to-Ambient	R <sub>thJA</sub>	100	°C/W



<b>Specifications</b> $T_J = 25^{\circ}C$ , u	111000 01110	- Wied Hoted		\/-l		
Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Тур.	Max.	
Static	i			,		
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_{D} = 250\mu A$	30			V
Zero Gate Voltage Drain Current	١,	$V_{DS} = 30V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	μA
Zero Gate Voltage Brain Gurrent	I <sub>DSS</sub>	$V_{DS} = 30V, V_{GS} = 0V, T_{J} = 100^{\circ}C$			25	μΛ
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20V$	-		±100	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0	1.7	2.4	<b>V</b>
Static Drain Source On Begintance		$V_{GS} = 10V, I_{D} = 30A$		3.6	5.0	mΩ
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	$V_{GS} = 4.5V, I_{D} = 30A$		5	7.0	mΩ
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = 10V, I <sub>D</sub> =20A	17.3			S
Dynamic	-			-		
Input Capacitance	C <sub>iss</sub>	V 0V		1608		
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0V,$ $V_{DS} = 15V,$		513		pF
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0MHz		297		
Total Gate Charge	Q <sub>g</sub>			62		
Gate-Source Charge	$Q_{gs}$	$V_{DD} = 15V, I_{D} = 50A,$ $V_{GS} = 10V$		7		nC
Gate-Drain Charge	$Q_{gd}$	. 65		13		
Turn-on Delay Time	t <sub>d(on)</sub>			13		
Turn-on Rise Time	t <sub>r</sub>	$V_{DD} = 15V, I_{D} = 50A,$		17		
Turn-off Delay Time	t <sub>d(off)</sub>	$R_G = 3\Omega$		42		ns
Turn-off Fall Time	t <sub>f</sub>			13		
Drain-Source Body Diode Character	istics					
Continuous Body Diode Current <sup>B</sup>	Is				46	_
Pulsed Diode Forward Current <sup>A</sup>	I <sub>SM</sub>	$T_C = 25^{\circ}C$			270	А
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25^{\circ}C$ , $I_{SD} = 30A$ , $V_{GS} = 0V$			1.2	V
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 30A,		40		ns
Reverse Recovery Charge	Q <sub>rr</sub>	$di_F/dt = 100A/\mu s$		88		nC

#### **Notes**

- 1. Repetitive Rating: Pulse Width limited by maximum junction temperature
- 2.  $V_{DD} = 30V$ ,  $R_G = 25\Omega$ , Starting  $T_J = 25^{\circ}C$
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 1%

### **Typical Characteristics** $T_J = 25^{\circ}\text{C}$ , unless otherwise noted

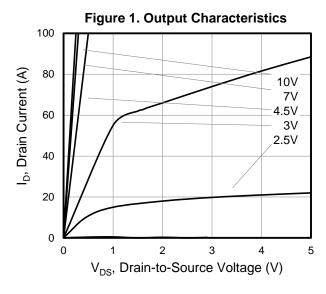


Figure 3. On-Resistance vs. Drain Current

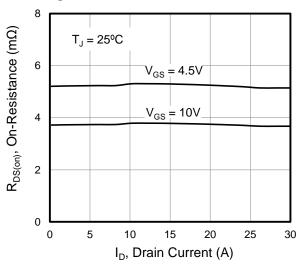


Figure 5. Gate Charge

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Figure 2. Transfer Characteristics

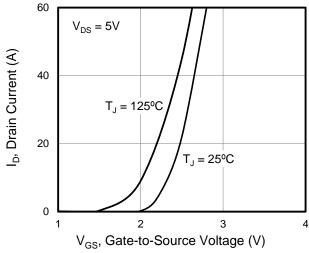


Figure 4. Capacitance

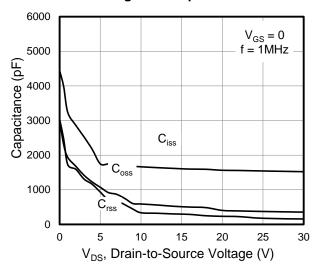
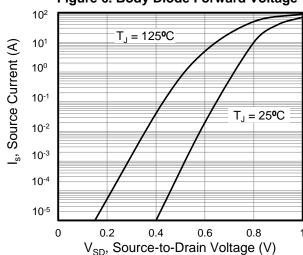


Figure 6. Body Diode Forward Voltage





## **Typical Characteristics** $T_J = 25^{\circ}\text{C}$ , unless otherwise noted

Figure 7. On-Resistance vs.

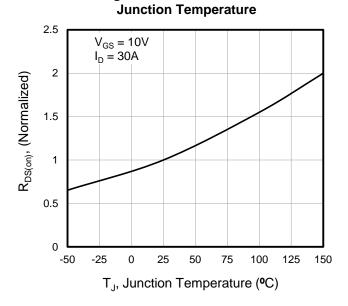


Figure 8. Threshold Voltage vs. Junction Temperature

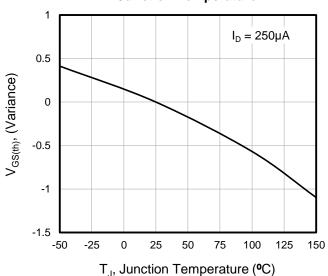


Figure 9. Transient Thermal Impedance

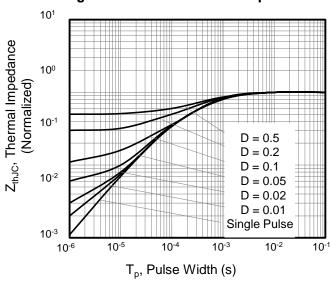


Figure 10. Safe operation area

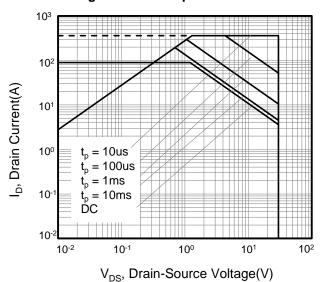




Figure A: Gate Charge Test Circuit and Waveform

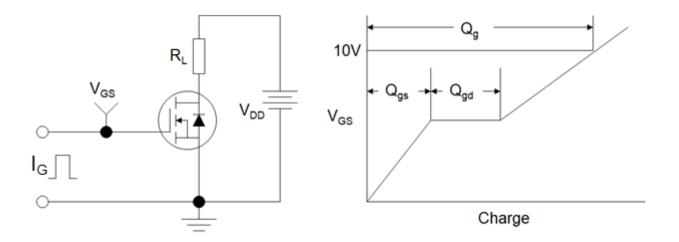


Figure B: Resistive Switching Test Circuit and Waveform

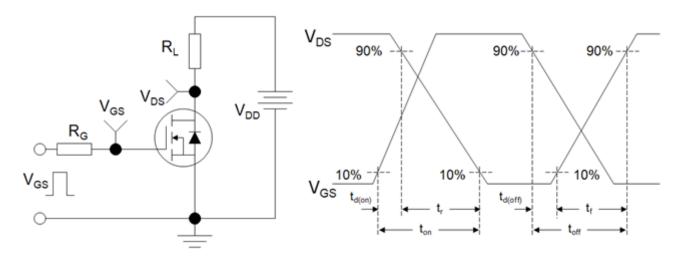
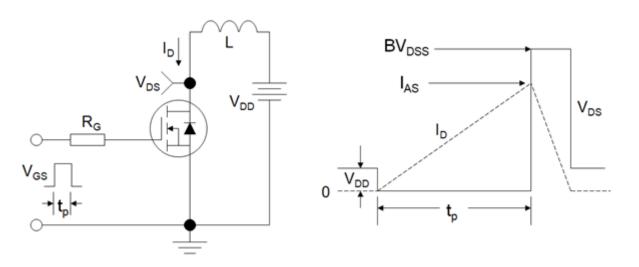
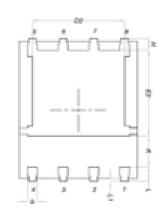


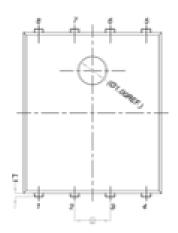
Figure C: Unclamped Inductive Switching Test Circuit and Waveform





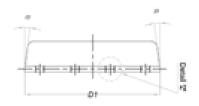
# DFN5x6(M)





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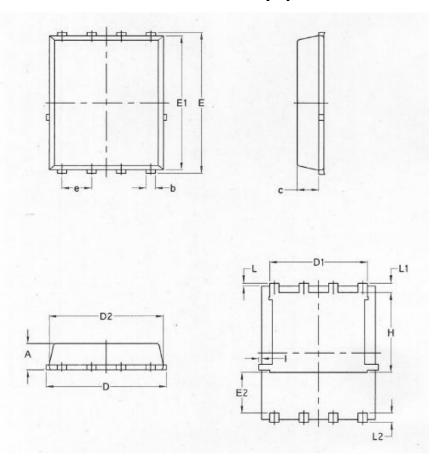




	M	IILLIMETI	ERS	0114	l. A	IILLIMETI	ERS
DIM.	MIN.	NOM.	MAX.	DIM.	MIN.	NOM.	MAX.
Α	0.90	1.00	1.10	E	5.90	6.00	6.10
A1	0	-	0.05	E1	5.70	5.75	5.80
b	0.33	0.41	0.51	E2	3.38	3.58	3.78
С	0.20	0.25	0.30	6		1.27 BSC	
D1	4.80	4.90	5.00	Н	0.41	0.51	0.61
D2	3.61	3.81	3.96	К	1.10	-	-
				L	0.51	0.61	0.71
				L1	0.06	0.13	0.20
				α	O°	-	12°



# DFN5x6(V)



	S						
	M B O	M	M	INCH			
	O.	MIN.	MAX.	MIN.	MAX.		
	Α	1.03	1.17	0.0406	0.0461		
	b	0.34	0.48	0.0134	0.0189		
	С	0.824	0.970	0.0324	0.0382		
1	D	4.80	5.40	0.1890	0.2126		
	D1	4.11	4.31	0.1618	0.1697		
R	D2	4.80	5.00	0.1890	0.1969		
	E	5.95	6.15	0.2343	0.2421		
	E1	5.65	5.85	0.2224	0.2303		
	E2	1.60	_	0.0630	-		
	е	1.27 BSC		0.05 BSC			
1	L	0.05	0.25	0.0020	0.0098		
	L1	0.38	0.50	0.0150	0.0197		
	L2	0.38	0.50	0.0150	0.0197		
4	Н	3.30	3.50	0.1299	0.1378		
	1	_	0.18	_	0.0070		



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